American Mineralogist, Volume 64, page 940, 1979

NOTICES

The Friends of Mineralogy, Northwest Chapter, will hold its 5th annual symposium, "Sulfides and Sulfosalts," on September 28–30, 1979, in Bellevue, Washington. Seven speakers and 10–20 non-competitive educational displays are planned, and three well-known dealers will be represented. For further information, contact

Mike Groben
Rt. 1, Box 16
Coos Bay, OR 97420
(telephone) 503–269–9032

Standard X-ray Diffraction Powder Patterns Section 15—Data for 112 Substances, by Marlene C. Morris, Howard F. McMurdie, Eloise H. Evans, Boris Paretzkin, Johan H. de Groot, Brenda S. Weeks, and Rainer J. Newberry of the International Centre for Diffraction Data, and Camden R. Hubbard and Simon J. Carmel of National Bureau of Standards. This book contains the latest addition of 112 compounds, both organic and inorganic, to the tables of X-ray diffraction patterns being compiled by a joint project of the National Bureau of Standards and the International Centre for Diffraction Data of the Joint Committee on Powder Diffraction Standards.

Of the 112 substances included in Section 15, 54 of the patterns represent experimental data and 58 are calculated. The experimental X-ray powder diffraction patterns were obtained with an X-ray diffractometer. Experimental techniques are described in the introduction. All *d* values were assigned Miller indices determined by comparison with computed interplanar spacings consistent with space group extinctions. The densities and lattice constants were calculated and the refractive indices were measured whenever possible. The calculated X-ray powder diffraction patterns were computed from published crystal structure data. Both peak height and integrated intensities are reported for the calculated patterns. This text also includes a cumulative index to the over 1400 X-ray powder diffraction patterns published to date by the project. These appeared in earlier volumes of NBS Monograph 25 or Circular 539, Vols. 1–10.

To order printed copies, send $4.00 ($5.00 foreign) to Superintendent of Documents, U.S. Government Printing Office, Washington, DC 20402. Designation MN-25, Section 15; stock number 003-003-01986-1. To order microfiche copies, send $3.00 ($4.50 foreign) to National Technical Information Service, Springfield, Virginia 22161; NTIS number NBS-MN-25, Section 15.

Index to the Reflectance and Microindentation Hardness of Ore Minerals in the IMA/COM Quantitative Data File (First Issue, 1977) by B. F. Leonard. U.S. Geological Survey Open-File Report 79-658, 1979. The COM Quantitative Data File Gives, on cards, the reflectance and microindentation hardness of a good selection of ore minerals. The 200 data cards are arranged alphabetically by mineral name and corresponding accession number. The numbering system accommodates multiple data cards for a given mineral and allows for expansion as new data are added to subsequent editions of the file. The first issue of the file contains an abundance of reflectance and microindentation hardness values of superior quality, but the lack of a direct index to the numerical data has inhibited the full and effective use of the file by the working ore microscopist.

This separately published index to numerical data in the COM Data File serves both as an index in the strict sense and as a set of determinative tables. As an index, it permits the user to find the reflectance and microhardness values that are recorded on the data cards. As a set of determinative tables, the index helps the user identify an unknown mineral, either directly from the index or after study of the data on the card found by use of the numerical index. The outline of the index is given, the arrangement of the contents of the index is explained, and the use of the index as a determinative table is illustrated.

This report is available from the U.S. Geological Survey, Open File Services Section, Branch of Distribution, Box 25425, Federal Center, Denver, Colorado 80225. $6.75 for printed copy, $3.50 for microfiche.